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APPLICATION NO. 09/862523	CONT/PRIOR	CLASS 348	SUBCLASS 308	ART UNIT 2612	EXAMINER	
Steven C Zhiliang Anli Liu	lynes Chen	•				
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On-chip	L SUBCLASS	ISSUING	G CLASSI	FICATIO	N FERENCE(S)	PTC-204 1299

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TERMINAL		DRAWINGS		CLAIMS ALLOWED		
DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G	
The term of this patent			· .	NOTICE OF ALLOWANCE MAILED		
subsequent to (date) has been disclaimed.	(Assistant Examiner)		(Date)	,		
The term of this patent shall not extend beyond the expiration date of U.S Patent. No.				ISSUE FEE		
				Amount Due	Date Paid	
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this patent have been disclaimed.	(Legal Instrum	ents Examiner)	(Date)	<u> </u>		